

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	2	capacit\$5 same leak same dielectric same coupling same electric\$4 near2 power same residual same charge same decoupl\$5	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/05/26 22:49
L2	2	capacit\$5 same leak same dielectric same coupling same electric\$4 near2 power same charge same decoupl\$5	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/05/26 22:49
L3	3	capacit\$5 same leak same dielectric same electric\$4 near2 power same charge same decoupl\$5	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/05/26 22:49
L4	4	capacit\$5 same leak same dielectric same electric\$4 near2 power same (decoupl\$5 or coupl\$5)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/05/26 22:49
L5	15	capacit\$5 same leak same dielectric same power same (decoupl\$5 or coupl\$5)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/05/26 22:49
L6	14	leak near5 dielectric same power same (decoupl\$5 or coupl\$5)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/05/26 22:49
L7	6	((("20020022961") or ("20040225199") or ("20040203413")).PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	OFF	2008/05/26 22:49
L8	0	levinson.in. and electronic.clm. and capacitive.clm. and power.clm.	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/05/26 22:49
L9	1	10/508865	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/05/26 22:49

L10	285	((electronic near1 (entity or device)) or (chip near1 card) or (ic near1 card) or (ic-card) or smartcard or smart-card or "smart card" or (microchip near1 card) or (micro-chip near1 card)) same elaps\$4 near2 time same (charg\$4 or power\$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/05/26 22:49
L11	5	((electronic near1 (entity or device)) or (chip near1 card) or (ic near1 card) or (ic-card) or smartcard or smart-card or "smart card" or (microchip near1 card) or (micro-chip near1 card)) same elaps\$4 near2 time same (charg\$4 or power\$4) and leak with dielectric\$4	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/05/26 22:49
L12	36	((electronic near1 (entity or device)) or (chip near1 card) or (ic near1 card) or (ic-card) or smartcard or smart-card or "smart card" or (microchip near1 card) or (micro-chip near1 card)) same elaps\$4 near2 time same (charg\$4 or power\$4) and (leak or dielectric\$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/05/26 22:49
L13	68	((electronic near1 (entity or device)) or (chip near1 card) or (ic near1 card) or (ic-card) or smartcard or smart-card or "smart card" or (microchip near1 card) or (micro-chip near1 card)) same external with (charg\$4 or power\$4) same coupl\$5 near15 switch\$4	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/05/26 22:49
L14	2556	switch\$4 near4 decoupl\$5 same (power\$4 or electr\$7)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/05/26 22:49
L15	133	switch\$4 near4 decoupl\$5 same (power\$4 or electr\$7) with (passive or external\$4 or separate)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/05/26 22:49

L16	3	("4063229").FN.	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	OFF	2008/05/26 22:49
L17	423	mos near5 capacit\$6 same dielectric same silicon with oxide	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/05/26 22:49
L18	153	mos near5 capacit\$6 same dielectric with silicon adj1 oxide	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/05/26 22:49
L19	45	mos near5 capacit\$6 near6 dielectric with silicon adj1 oxide	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/05/26 22:49
L20	1881	"10 nm" with insulat\$4 near4 (medium or layer)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/05/26 22:49
L21	194	"10 nm" with insulat\$4 near4 (medium or layer) same (storage or capacit \$5)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/05/26 22:49
L22	55	"10 nm" near5 insulat\$4 near4 (medium or layer) same (storage or capacit \$5)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/05/26 22:49

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